
THE BALLISTIC ELECTRON EMISSION MICROSCOPY

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Ballistic Electron Emission Microscopy (BEEM) is a technique, based on scanning tunneling microscopy, which allows the study of potential steps at interfaces with high lateral resolution. In this respect, especially metal/semiconductor junctions are of great technical interest, and a good understanding of their electronic and structural properties, in particular of the potential barrier at the interface (the Schottky barrier height), is needed. A large variety of techniques, such as current- voltage measurements or photoelectron spectroscopy, has been used to investigate these properties, but most of them either show a lack of spatial resolution or are too surface sensitive. BEEM however provides an alternative approach for the investigation of buried interfaces with nanometer resolution of the junction up to a metal substrate thickness of around 100 - 300Å .

REMARKABLE THERMAL STABILITY OF CONDUCTIVITY OF POLYANILINE/MCM-41 COMPOSITE

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Polyaniline (PANI) has been synthesized in mesoporous silica MCM-41 by in situ polymerization method. Before the polymerization, MCM-41 was functionalized with sulfonic acid in order to increase interfacial interaction between PANI and MCM-41. Aniline hydrochloric acid salt solution was sorbed into MCM-41 loaded with sulfonic acid. Oxidative polymerization was achieved by addition an aqueous solution of peroxydisulfate on the loaded MCM-41. Structure and properties of the conducting polymer composite samples were characterized by X-ray diffraction (XRD), Fourier Transform Infrared (FTIR), UV-Vis, thermogravimetric analysis (TGA) and Four Point Probe for conductivity measurement. It is revealed that although conductivity measurement shows that conductivity of PANI was reduced after addition of MCM-41, its thermal stability of conductivity was significantly enhanced and demonstrated the desirability and efficacy of this polymer-mesoporous silica MCM-41 composite system in relatively high temperature applications.